

Design-for-destability-based external test and diagnosis of mesh-like network- on-a-chips

Raik, Jaan; Govind, Vineeth; **Ubar, Raimund-Johannes** IET computers and digital techniques 2009 / 5, p. 476-486 : ill
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FPGA-based fault emulation of synchronous sequential circuits

Ellervee, Peeter; **Raik, Jaan**; Tammemäe, Kalle; **Ubar, Raimund-Johannes** IET computers and digital techniques 2007 / 2, p. 70-76 : ill <https://ieeexplore.ieee.org/abstract/document/1423822>

Test methods for crosstalk-induced delay and glitch faults in network-on-chip interconnects implementing asynchronous communication protocols

Bengtsson, Tomas; Kumar, Shashi; **Ubar, Raimund-Johannes**; **Jutman, Artur**; Peng, Zebo IET computers and digital techniques 2008 / 6, p. 445-460